

AP30N30WI

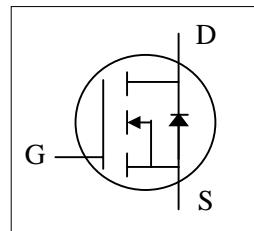
Pb Free Plating Product



**Advanced Power
Electronics Corp.**

**N-CHANNEL ENHANCEMENT MODE
POWER MOSFET**

- ▼ 100% Avalanche Test
- ▼ Simple Drive Requirement
- ▼ Lower On-resistance
- ▼ RoHS Compliant

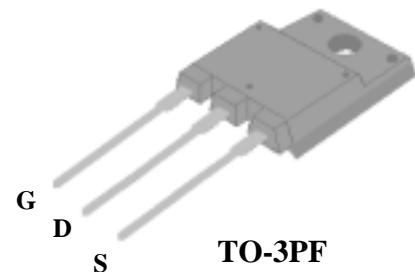


BV_{DSS}	250V
$R_{DS(ON)}$	68mΩ
I_D	30A

Description

AP30N30 from APEC provide the designer with the best combination of fast switching , low on-resistance and cost-effectiveness .

The TO-3PF fullpack eliminates the need for additional insulating hardware in commercial-industrial applications.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	250	V
V_{GS}	Gate-Source Voltage	± 30	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	30	A
I_{DM}	Pulsed Drain Current ¹	120	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation	83	W
	Linear Derating Factor	0.7	W/°C
E_{AS}	Single Pulse Avalanche Energy ³	450	mJ
I_{AR}	Avalanche Current	30	A
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Units
R_{thj-c}	Thermal Resistance Junction-case	Max. 1.5	°C/W
R_{thj-a}	Thermal Resistance Junction-ambient	Max. 42	°C/W



Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=10\text{mA}$	250	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_D=10\text{mA}$	-	0.24	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_D=15\text{A}$	-	-	68	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=1\text{mA}$	1.5	-	3.5	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}$, $I_D=15\text{A}$	-	23	-	S
I_{DSS}	Drain-Source Leakage Current ($T_j=25^\circ\text{C}$)	$V_{\text{DS}}=250\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	1	μA
	Drain-Source Leakage Current ($T_j=125^\circ\text{C}$)	$V_{\text{DS}}=250\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	200	μA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}= \pm 30\text{V}$	-	-	± 1	μA
Q_g	Total Gate Charge ²	$I_D=15\text{A}$	-	63	100	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=200\text{V}$	-	19	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=10\text{V}$	-	14	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time ²	$V_{\text{DS}}=125\text{V}$	-	28	-	ns
t_r	Rise Time	$I_D=15\text{A}$	-	36	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_G=10\Omega$, $V_{\text{GS}}=10\text{V}$	-	84	-	ns
t_f	Fall Time	$R_D=8.3\Omega$	-	45	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	4290	6900	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	550	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	6	-	pF
R_g	Gate Resistance	f=1.0MHz	-	1.9	3	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_S=30\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.5	V
t_{rr}	Reverse Recovery Time ²	$I_S=15\text{A}$, $V_{\text{GS}}=0\text{V}$	-	235	-	ns
Q_{rr}	Reverse Recovery Charge	dl/dt=100A/ μs	-	2.24	-	μC

Notes:

- 1.Pulse width limited by safe operating area.
- 2.Pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$.
- 3.Starting $T_j=25^\circ\text{C}$, $V_{\text{DD}}=50\text{V}$, $L=1\text{mH}$, $R_G=25\Omega$, $I_{\text{AS}}=30\text{A}$.

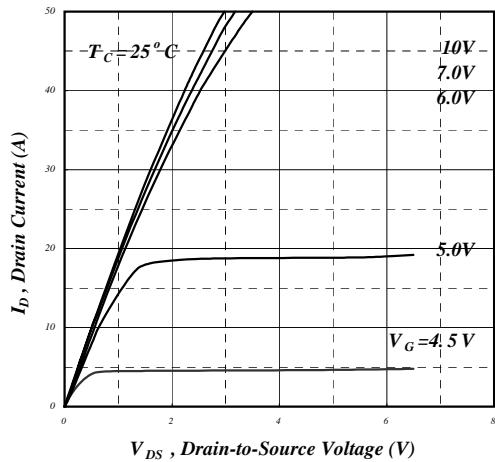


Fig 1. Typical Output Characteristics

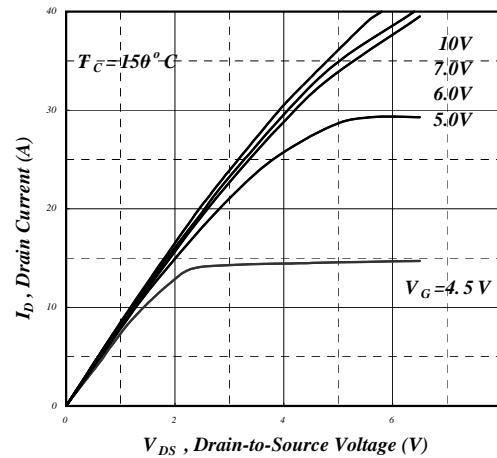


Fig 2. Typical Output Characteristics

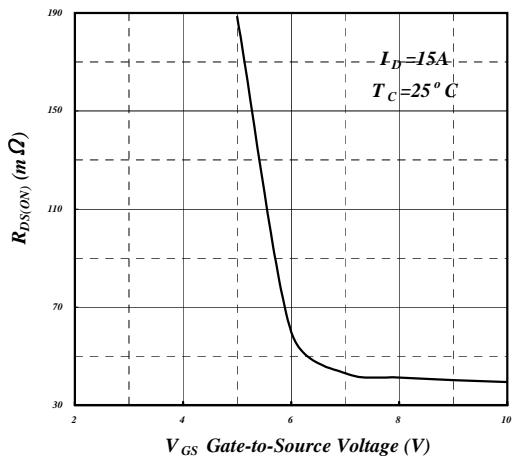


Fig 3. On-Resistance v.s. Gate Voltage

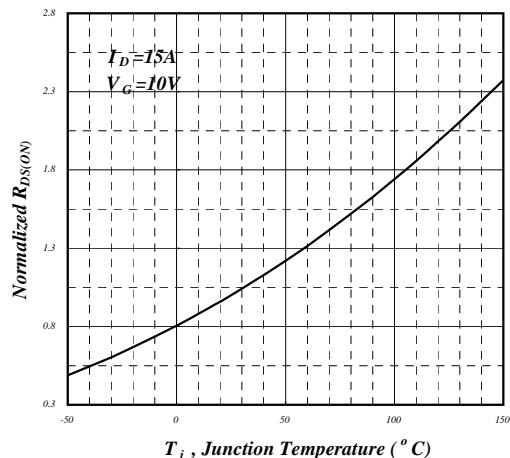


Fig 4. Normalized On-Resistance v.s. Junction Temperature

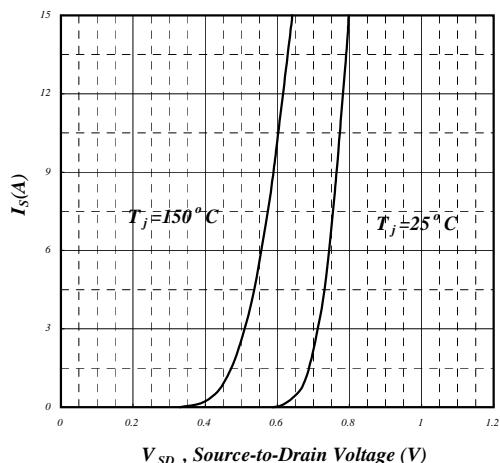


Fig 5. Forward Characteristic of Reverse Diode

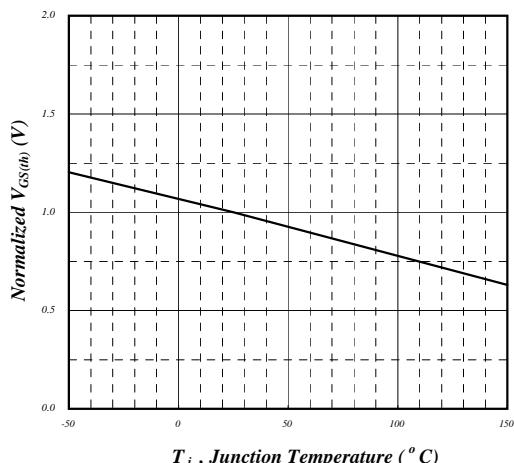


Fig 6. Gate Threshold Voltage v.s. Junction Temperature



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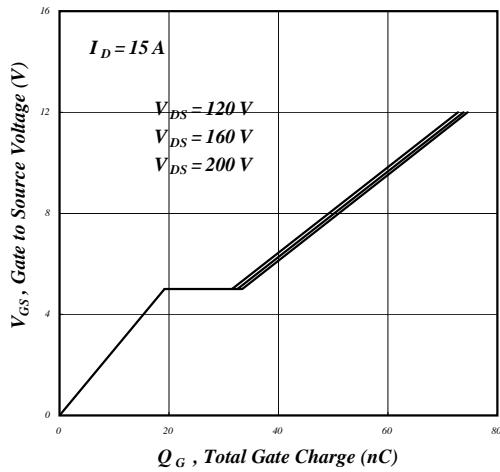


Fig 7. Gate Charge Characteristics

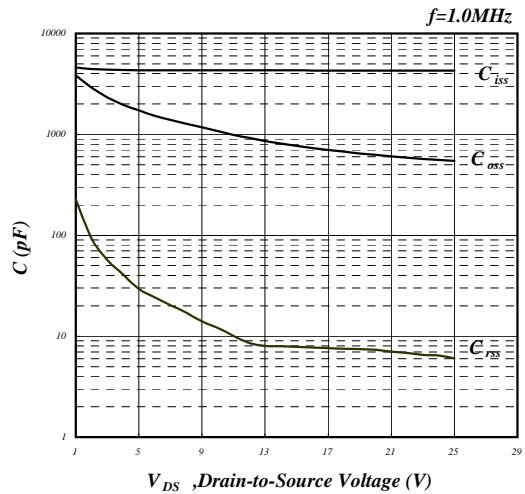


Fig 8. Typical Capacitance Characteristics

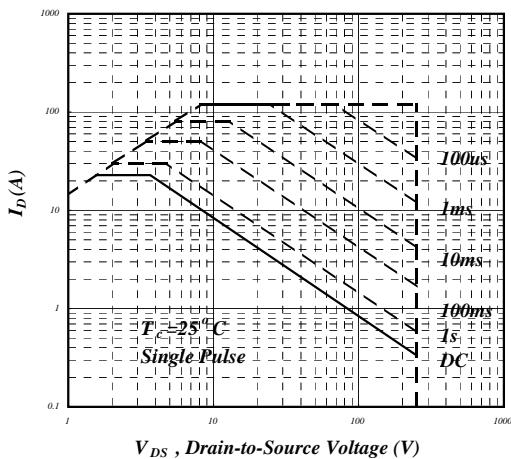


Fig 9. Maximum Safe Operating Area

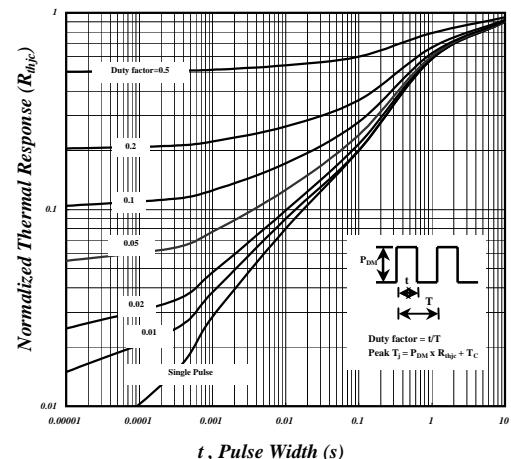


Fig 10. Effective Transient Thermal Impedance

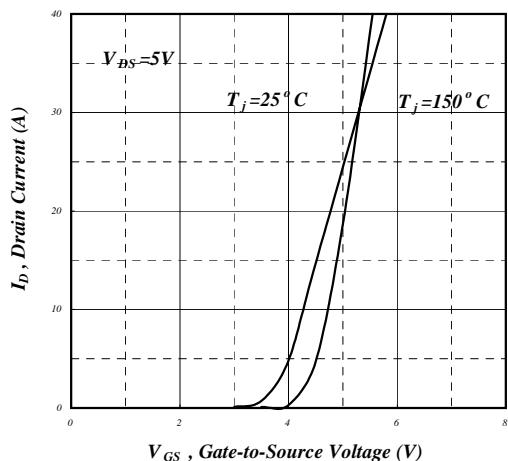


Fig 11. Transfer Characteristics

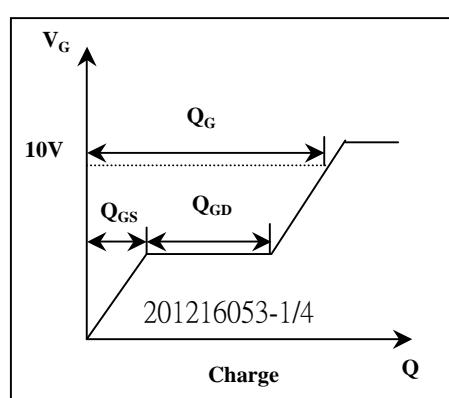


Fig 12. Gate Charge Waveform